

U.S. Application No. 10/655,719

Amendments to the Claims:

Listing of Claims:

1. (Previously Presented) A method of detecting a portion of a half-toned uniform area in a half-toned bit-map comprising:

partitioning a half-toned bit map into a plurality of N-pixel tiles, each N-pixel tile having a marked pixel count M, and wherein the half-toned bit map is produced pursuant to a predetermined half-toning procedure, and wherein each N-pixel tile is produced from an associated portion of pre-half-toned data;

comparing each N-pixel tile to a corresponding N-pixel reference tile that comprises a half-toned binary pattern that would be produced by the predetermined half-toning procedure for such N-pixel tile if the portion of a pre-half-toned data that resulted in such N-pixel tile were of uniform lightness;

identifying an N-pixel tile as comprising a portion of a half-toned uniform region if it matches the corresponding N-pixel reference tile.

2. (Original) The method of claim 1 wherein comparing each N-pixel tile to an N-pixel reference tile comprises comparing each N-pixel tile to an associated N-pixel reference tile that comprises a half-toned binary pattern that would be produced by the predetermined half-toning procedure for such N-pixel tile if the portion of the original data that resulted in such N-pixel tile were of uniform lightness, wherein the N-pixel reference tile includes the same number of marked pixels M as the N-pixel tile to which it is being compared.

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3. (Previously Presented) A method of detecting a uniform area in a half-toned bit map comprising:

partitioning a half-toned bit map into a plurality of N-pixel tiles, each N-pixel tile having a marked pixel count M, wherein the half-toned bit map is produced pursuant to a predetermined threshold value array, and wherein each N-pixel tile is produced from an associated portion of original data;

comparing each N-pixel tile to an associated N-pixel reference tile that comprises a half-toned binary pattern that would be produced for such N-pixel tile pursuant to the predetermined threshold value array if the portion of the original data that resulted in such N-pixel tile were of uniform lightness;

identifying an N-pixel tile as comprising a portion of a half-toned uniform region if it matches the corresponding N-pixel reference tile.

4. (Previously Presented) The method of claim 3 wherein comparing each N-pixel tile to an N-pixel reference tile comprises comparing each N-pixel tile to an associated N-pixel reference tile that comprises a half-toned binary pattern that would be produced for such N-pixel tile pursuant to the predetermined threshold value array if the portion of the original data that resulted in such N-pixel tile were of uniform lightness, wherein the N-pixel reference tile includes the same number of marked pixels M as the N-pixel tile to which it is being compared.

5. (Previously Presented) The method of claim 3 wherein comparing each N-pixel tile to an N-pixel reference tile comprises comparing each N-pixel tile to an associated N-pixel reference tile that comprises a half-toned binary pattern that would be produced for such N-pixel tile pursuant to the predetermined threshold value array if the portion of the original data that resulted in such N-pixel tile were of uniform lightness, wherein the pixels of the N-pixel reference tile are filled pursuant to a fill order that is based on the half-tone threshold values that produced such N-pixel tile.

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6. (Canceled)

7. (Previously Presented) The method of claim 3 wherein comparing each N-pixel tile to an N-pixel reference tile comprises comparing each N-pixel tile to an associated N-pixel reference tile that comprises a half-toned binary pattern that would be produced for such N-pixel tile pursuant to the predetermined threshold value array if the portion of the original data that resulted in such N-pixel tile were of uniform lightness, wherein the pixels of the N-pixel reference tile are filled pursuant to a fill order pattern of fill order values that comprise a sequence that corresponds to a relative ordering of the half-tone threshold values that produced such N-pixel tile, wherein the fill order values are between 1 and N.

8. (Previously Presented) A method of detecting a portion of a half-toned uniform area in a half-toned bit map comprising:

partitioning a half-toned bit map into a plurality of N-pixel tiles, each N-pixel tile having a marked pixel count M, wherein the half-toned bit map is produced pursuant to a predetermined threshold value array, and wherein each N-pixel tile is produced pursuant to associated half-tone threshold values;

comparing each N-pixel tile to a corresponding N-pixel reference tile that comprises a half-toned binary pattern that comprises a portion of a half-toned uniform region and is based on the half-tone threshold values that produced the N-pixel tile;

identifying an N-pixel tile as comprising a portion of a half-toned uniform region if it matches the corresponding N-pixel reference tile.